


Search Notes 	Application/Control No. 10711310	Applicant(s)/Patent Under Reexamination TAI ET AL.
	Examiner Chawan, Sheela C	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	141, 145, 149, 152, 147,	10/15/07	SCC
118	730, 715,	"	SCC
700	121, 110, 109,	"	"
702	30, 122, 35,	"	"
356	394, 237.1, 238.3, 237.5, 388,	"	"
438	5	"	"
257	E21.525, E21.53,	"	"
348	126, 86, 125, 92,	"	"
382	145, 149	5/23/08	SCC
700	110	5/23/08	SCC
702	35	5/23/08	SCC
348	126	5/23/08	SCC
ABOVE SEARCH UP-DATE.		5/23/08	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATABASE.	10/15/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE ATTACHED SEARCH HISTORY.	5/23/08	SCC
382/ 141, 145, 149, 152, 147.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	5/23/08	SCC
700/121, 110, 109.CCLS.	5/23/08	SCC
"	5/23/08	SCC
702/30, 122, 35.CCLS.	5/23/08	SCC
"	5/23/08	SCC
348/126, 86, 125, 92.CCLS.	5/23/08	SCC
"	5/23/08	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	5/23/08	SCC
SEARCH IEEE OR INSPEC DATA BASE.	5/23/08	SCC
ABOVE SEARCH UP DATED .	5/23/08	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	145, 149	5/23/08	SCC
700	110	5/23/08	SCC
702	35	5/23/08	SCC
348	126	5/23/08	SCC